

**LIST OF PATENTS  
AND PUBLICATIONS****23672****10/587,130**

APPLICANT

**Bernd RECH et al**

FILING DATE

**28 December 2007**

GROUP

**1794****U.S. PATENT DOCUMENTS**

EX. INIT		DOCUMENT NO. Cntry code - No.	DATE MM-YYYY	NAME	CLASS	SUB-CLASS	FILING DATE IF APPROPRIATE
	AA	US-					
	BB	US-					
	CC	US-					

**FOREIGN PATENT DOCUMENTS**

		DOCUMENT NO. Cntry Code - No.	DATE MM-YYYY	COUNTRY	NAME	CLASS	TRANSL.	
							YES	NO
	AI	WO 0246490	06/2003	WIPO	SZYSZKA et al			x
	AJ							
	AK							
	AL							
	AM							
	AN							
	AO							

**OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)**

	AR	Wallendorf et al: "Optical investigation in a PEM controlled reactive magnetron sputter process for aluminum doped zinc oxide layers using metallic alloy targets", Surface and Coatings Technology Vol. 147-175 (2003) pages 222-228
	AS	Szyszkka et al: "Transparent and conductive ZnO:A1 film deposited by large area reactive magnetron Sputtering", Thin Solid Films vol. 442 (2003) pages 179-183
	AT	Jaeger et al: "Comparison of transparent conductive oxide thin films prepared by a.c. and d.c. reactive magnetron sputtering" Surface and Coatings Technology, vol. 98 (1998), pages 1304-1314
		Bartzsch et al: "Modeling the stability of reactive sputtering processes", Surface and Coatings Technology vol 142-144 (2001), pages 192-200
		Szyszkka et al: "Optical and electrical properties of doped zinc oxide film prepares by ac reactive magnetron sputtering" Journal of Non-Crystalline Solids, vol 218, (1997) pages 74-80
		Malkomes et al: "Properties of aluminum-doped zinc oxide films deposited by high rate mid-frequency magnetron sputtering" J. Vac. Sci. Technol. A, vol. 19, no.2 (2001), pages 414-419
		Mueller et al: "State-of-the-art mid-frequency sputtered ZnO films for thin film silicon solar cells and modules" Thin solid films, vol. 442 (2003), pages 158-162
		Szyszkka: "Transparent and conductive aluminum doped zinc oxide films prepared by mid-frequency reactive magnetron sputtering" Thin solid films, vol. 351 (2003), pages 164-169

EXAMINER  
**Katz, V**

DATE CONSIDERED

EXAMINER: Initial if Reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

8 December 2009